

THVD8010 RS-485 Transceiver with OOK Modulation for Power Line Communication

1 Features

- 3-V 5.5-V supply voltage
- Half-duplex communication
 - Up to 30 Kbps data rate (OOK)
- RS-485 electrical signaling with on-off keying (OOK) modulation
- Polarity Free
- Good noise immunity
- Pin selectable carrier frequency: 125 kHz 300
- Spread spectrum clocking for excellent EMI performance
- TX timeout to avoid stuck bus conditions
- Operational common-mode range: -7 V to 12 V
- Bus I/O protection
 - ± 18-V DC fault protection
 - ± 16 kV HBM ESD
 - ± 8 kV IEC 61000-4-2 contact discharge
 - ± 15 kV IEC 61000-4-2 air gap discharge
 - ± 4 kV IEC 61000-4-4 fast transient burst
- Extended temperature range: -40°C to 125°C
- 8-Pin SOT-23 package for space constrained applications

2 Applications

- **HVAC** systems
- **Building automation**
- Factory automation & control
- **Appliances**
- Lighting
- Grid infrastructure

3 Description

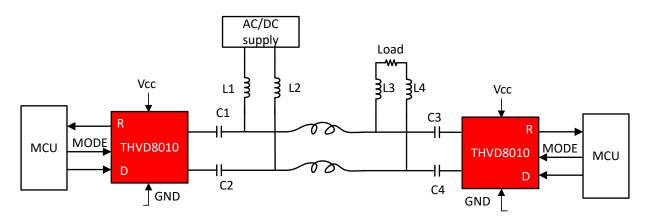
THVD8010 is an RS-485 transceiver with on-off keying (OOK) modulation and demodulation built in for power line communication. Modulating data onto existing power lines allows power delivery and data communication to share a common pair of wires, resulting in a significant reduction of the system cost.

A pin programmable interface simplifies the system design. The carrier frequency can be adjusted by changing an external resistor on the F SET pin. A broad range of carrier frequencies gives the system designer the flexibility to choose the external inductors and capacitors. In addition, OOK modulation operates with immunity to data polarity for ease of system installations.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
THVD8010	SOT-23 (8)	2.90 mm × 1.60 mm

For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Schematic



Table of Contents

1 Features1	8.1 Overview15
2 Applications 1	8.2 Functional Block Diagrams15
3 Description1	8.3 Feature Description15
4 Revision History2	8.4 Device Functional Modes17
5 Pin Configuration and Functions3	9 Application and implementation18
Pin Functions3	9.1 Application information18
6 Specifications4	9.2 Typical application (OOK mode)18
6.1 Absolute Maximum Ratings4	10 Power supply recommendations20
6.2 ESD Ratings 4	11 Layout21
6.3 ESD Ratings - IEC Specifications4	11.1 Layout guidelines21
6.4 Recommended Operating Conditions4	11.2 Layout Example21
6.5 Thermal Information5	12 Device and Documentation Support22
6.6 Electrical Characteristics5	12.1 Device Support
6.7 Power Dissipation Characteristics8	12.2 Receiving Notification of Documentation Updates22
	12.3 Support Resources22
	12.4 Trademarks22
7 Parameter Measurement Information10	12.5 Electrostatic Discharge Caution22
8 Detailed Description15	12.6 Glossary22
6.8 Switching Characteristics	12.3 Support Resources

4 Revision HistoryNOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
November 2020	*	Initial release.

5 Pin Configuration and Functions

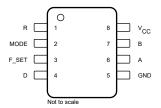


Figure 5-1. DRL Package, 8-Pin SOT-23, Top View

Pin Functions

PIN NAME NO.		1/0	DESCRIPTION
		- I/O	DESCRIPTION
R	1	Digital output	Receive data output
MODE	2	Digital input	Transmit/receive mode selection. Low = receive mode; High = transmit mode. Has an internal 2-M Ω pull-down to GND
F_SET	3	Analog input	Carrier frequency selection. Use a resistor to GND to select a frequency.
D	4	Digital input	Driver data input, 2-MΩ pull-up to V _{CC}
GND	5	Ground	Device ground
A	6	Bus input/output	Bus I/O port A (complementary to B)
В	7	Bus input/output	Bus I/O port B (complementary to A)
V _{CC}	8	Power	3.3-V to 5-V device supply



6 Specifications

6.1 Absolute Maximum Ratings

see (1)

		MIN	MAX	UNIT
V _{CC}	Supply voltage	-0.5	7	V
V _L	Input voltage at any logic pin (D, MODE or F_SET)	-0.3	5.7	V
V _A , V _B	Voltage at A or B inputs (differential or with respect to GND)	-18	18	V
Io	Receiver output current	-24	24	mA
TJ	Junction temperature		170	°C
T _{STG}	Storage temperature	-65	150	°C

⁽¹⁾ Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under *Section 6.4* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

				VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC	A and B pins to GND	±16,000	
V _(ESD)	Electrostatic	JS-001 ⁽¹⁾	All pins	±4,000	V
· (ESD)	discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	All pins	±16,000	V

⁽¹⁾ JEDEC document JEP155 states that 500-V HBM allows safemanufacturing with a standard ESD control process.

6.3 ESD Ratings - IEC Specifications

			VALUE	UNIT	
V _(ESD)	Electrostatic discharge	IEC 61000-4-2 ESD contact discharge, A and B pins to GND	±8		
		IEC 61000-4-2 ESD air gap discharge, A and B pins to GND	±15	kV	
		IEC 61000-4-4 electrical fast transient, A and B pins to GND	±4		

6.4 Recommended Operating Conditions

			N	IIN	NOM	MAX	UNIT
V _{CC}	Supply voltage			3		5.5	V
V _{ID}	Input differential voltage (A and B pir	ns)		-7		12	V
V _{CM}	perational common mode voltage (A and B pins)			-7		12	V
V _{IH}				2		V_{CC}	V
V_{IL}	Low-level input voltage (D and MOD	E pins)		0		8.0	V
	Output ourrent	Driver	-	-60		60	mΛ
lo	Output current	Receiver		-4		4	mA
R _{F_SET}	Carrier frequency selection resistor			32		80	kΩ
ΔR F_SET	Carrier frequency selection resistor t	olerance		-2		2	%
1/t _{UI}	Data rate	Modulation mode ⁽¹⁾				f ₀ / 10	bps
C _{F_SET}						100	pF
T _A	Operating ambient temperature		-	-40		125	°C

⁽¹⁾ f_0 is the carrier frequency (in Hz) set by the external resistor between F_SET and GND pins.

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⁽²⁾ JEDEC document JEP157 states that 250-V CDM allows safemanufacturing with a standard ESD control process.



6.5 Thermal Information

		THVD8010	
	THERMAL METRIC ⁽¹⁾	DDF (SOT-23)	UNIT
		8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	106.6	°C/W
R ₀ JC(top)	Junction-to-case (top) thermal resistance	38.4	°C/W
R _{0JB}	Junction-to-board thermal resistance	29.9	°C/W
ΨЈТ	Junction-to-top characterization parameter	1.9	°C/W
ΨЈВ	Junction-to-top characterization parameter	29.5	°C/W

⁽¹⁾ For more information about traditional and new thermalmetrics, see the Semiconductor and ICPackage Thermal Metrics application report.

6.6 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted). All typical values are at 25° C and supply voltage of V_{CC} = 5 V.

	PARAMETER	TEST CONDITIO	NS	MIN	TYP	MAX	UNIT
Driver			-			<u>'</u>	
		OOK mode, R_L = 60 Ω , -7 V ≤ V_{test} ≤ 12 V, Measured at 2nd pulse	See Figure 7-1	1.5	2		
V _{OD}	Driver differential output voltage magnitude	OOK mode, $R_L = 100 \Omega$, $C_L = 50$ pF, Measured at 2nd pulse	See Figure 7-1	2	2.5		V
		OOK mode, R_L = 54 Ω , C_L = 50 pF, Measured at 2nd pulse	See Figure 7-1	1.5	2		
V _{OC}	Steady state common-mode output voltage	OOK mode, R_L = 60 Ω , C_L = 50 pF	See Figure 7-2	1	V _{CC} / 2	3	V
ΔV _{OC}	Change in differential driver common-mode output voltage	OOK mode, R_L = 60 Ω , C_L = 50 pF	See Figure 7-2	-160		160	mV
V _{OC(PP)}	Peak-to-peak driver common-mode output voltage	OOK mode, R_L = 60 Ω , C_L = 50 pF, V_{CC} = 3.3 V and V_{CC} = 5V	See Figure 7-2		450		mV
I _{OS}	Driver short-circuit output current	OOK mode, MODE = V _{CC} , -7 \ 12 V	$V \leq [V_A \text{ or } V_B] \leq$	-250		250	mA
f_0	Minimum carrier frequency ⁽¹⁾	$R_{F_SET} = 77 \text{ k}\Omega$	See Figure 7-3		125		kHz
f_0	Maximum carrier frequency ⁽¹⁾	R_{F_SET} = 31.9 k Ω	See Figure 7-3		300		kHz
DCD _{f0}	Carrier frequency duty cycle distortion	Measured over the full range o	f f ₀	-2		2	%
Δf_0	Carrier frequency tolerance	Measured with a ±2% tolerant	R _{F_SET}	-25		25	%
Δf _{SSC}	Variation of the carrier frequency for spread spectrum clocking	Measured across the full carrie range	r frequency		±5		%
f _{SSC}	Spread spectrum clock rate				30		kHz



6.6 Electrical Characteristics (continued)

over operating free-air temperature range (unless otherwise noted). All typical values are at 25° C and supply voltage of $V_{CC} = 5 \text{ V}$.

	PARAMETER	TEST CONDITION	ONS	MIN	TYP	MAX	UNIT
Receiver							
	Bus input current in receive	MODE = GND, V _{CC} = 0 V or	V _I = 12 V		75	125	
l _l	mode	5.5 V	V _I = -7 V	-97	-70		μΑ
V_{MAG_ZERO}	OOK signal differential swing (magnitude) to detect a zero at the R output	MODE = GND, over full common mode range, OOK mode	125 kHz			1200	mV
V _{MAG_ZERO}	OOK signal differential swing (magnitude) to detect a zero at the R output		200 kHz			1200	mV
V _{MAG_ZERO}	OOK signal differential swing (magnitude) to detect a zero at the R output	MODE = GND, over full common mode range, OOK mode	300 kHz			1300	mV
V _{MAG_ONE}	OOK signal differential swing (magnitude) to detect an one at the R output	MODE = GND, over full common mode range, OOK mode	125 kHz	400			mV
V _{MAG_ONE}	OOK signal differential swing (magnitude) to detect an one at the R output		200 kHz	400			mV
V _{MAG_ONE}	OOK signal differential swing (magnitude) to detect an one at the R output		300 kHz	400			mV
V _{MAG_HYS}	Receiver differential input voltage threshold hysteresis		125 kHz	350			mV
V _{MAG_HYS}	Receiver differential input voltage threshold hysteresis		200 kHz	350			mV
V _{MAG_HYS}	Receiver differential input voltage threshold hysteresis	MODE = GND, over full common mode range, OOK mode	300 kHz	350			mV
Logic / Cont	rol Pins						
I _{IN}	Input current (D, MODE)	V _O = 0 V or V _{CC}	V _O = 0 V or V _{CC}	-5		5	μA
I _{IN}	Input current (F_SET)	$V_O = V_{CC}$	V _O = V _{CC}			55	μA
	Outrot willtown (F. OFT)	I _O = 0 mA			1.4		V
V _O	Output voltage (F_SET)	32 kΩ ≤ R _{PD} ≤ 78 kΩ			785		mV
V _{OH}	Receiver high-level output voltage	I _{OH} = -4 mA	I _{OH} = -4 mA	V _{CC} - 0.4	V _{CC} - 0.2		V
V _{OL}	Receiver low-level output voltage	I _{OL} = 4 mA			0.2	0.4	V
l _{oz}	Receiver high-impedance output current	$V_O = 0 \text{ V or } V_{CC}, \text{ MODE} = 0$		-1		1	μA
Device						1	
I _{cc}	Supply current (quiescent)	OOK transmit mode	D = V _{CC} , MODE = V _{CC} , resistor between F_SET and GND, no load		3	5	mA
I _{CC}	Supply current (quiescent)	OOK receive mode	D = V _{CC} , MODE = GND, resistor between F_SET and GND, no load		3.8	6	mA



6.6 Electrical Characteristics (continued)

over operating free-air temperature range (unless otherwise noted). All typical values are at 25° C and supply voltage of $V_{CC} = 5 \text{ V}$.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
T _{SD}	Thermal shutdown temperature		160	170	185	°C
T _{HYS}	Thermal shutdown hysteresis			11	15	°C

⁽¹⁾ See OOK modulation section for the complete carrier frequency range



6.7 Power Dissipation Characteristics

over operating free-air temperature range (unless otherwise noted). All typical values are at 25° C and supply voltage of V_{CC} = 5 V.

	PARAMETER	TEST C	MIN	TYP	MAX	UNIT	
PD	Chin power dissination in OOK made	MODE = V _{CC} , R _L	f ₀ = 125 kHz, 12.5 kHz (25 kbps) clock pattern as data		60	85	mW
оок		= 60Ω , no C_L , see Figure 2	f ₀ = 300 kHz, 30 kHz (60 Kbps) clock pattern as data		90	130	mW

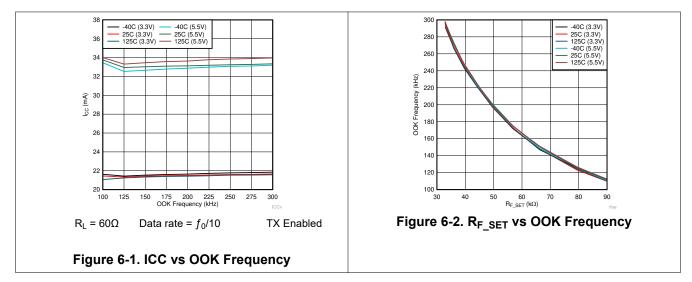
6.8 Switching Characteristics

over operating free-air temperature range (unless otherwise noted). All typical values are at 25° C and supply voltage of $V_{CC} = 5 \text{ V}$.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Driver						
t _r , t _f	Driver differential output rise and fall times			8	30	ns
t _{PHL} , t _{PLH}	Driver propagation delay	$R_L = 60 \Omega$, $C_L = 50 pF$, See Figure 7-4		1	3.5	Clocks
t _{SK(P)}	Driver pulse skew, t _{PHL} - t _{PLH}			1	2.5	Clocks
Receiver						
t _r , t _f	Receiver output rise and fall times			2	8	ns
t _{PHL} , t _{PLH}	Receiver propagation delay time	C _L = 15 pF, See Figure 7-5		4.5	6	Clocks
t _{SK(P)}	Receiver pulse skew, t _{PHL} - t _{PLH}			0.4	3	CIOCKS
Device					'	
t _{TX-RX_OOK}	Transmit to receive mode change delay, OOK mode	Max of t _{TX-RX_OOK_ZERO} and t _{TX-RX_OOK_ONE} . See Figure 7-6 and Figure 7-7			14	clocks
t _{RX-TX_OOK}	Receive to transmit mode change delay, OOK mode	See Figure 7-8			3	clocks
t _{TX_TIMEOUT}	Transmit timeout delay		60	110		S

Product Folder Links: THVD8010

6.9 Typical Characteristics





7 Parameter Measurement Information

Note

The number of pulses shown is reduced for simplicity of waveform. Please see the "OOK Modulation with F SET pin" section for more information.

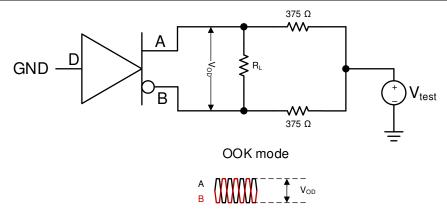


Figure 7-1. Measurement of Driver Differential Output Voltage With Common-Mode Load

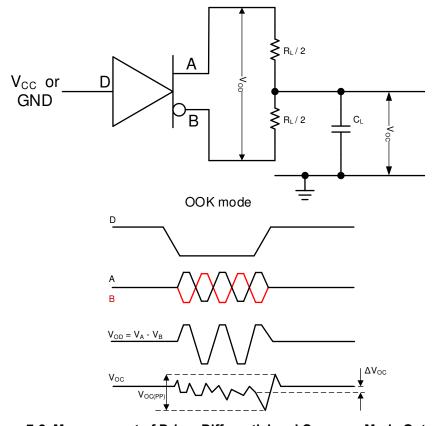


Figure 7-2. Measurement of Driver Differential and Common-Mode Outputs

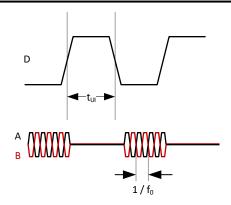


Figure 7-3. Measurement of Carrier Frequency

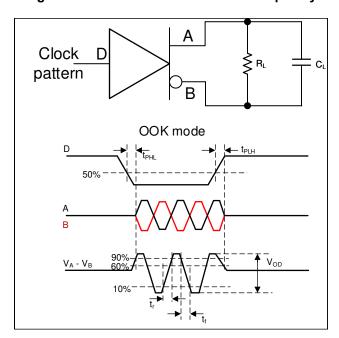


Figure 7-4. Measurement of Driver Switching Characteristics



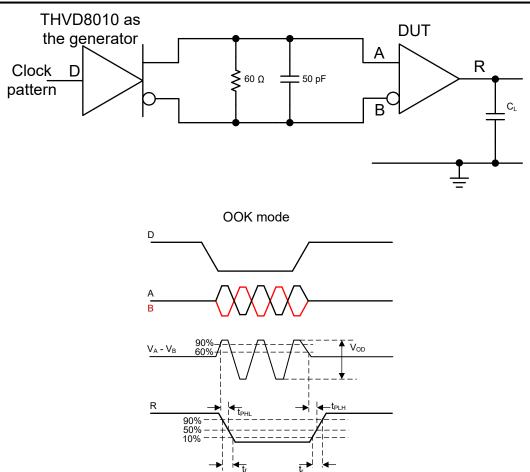
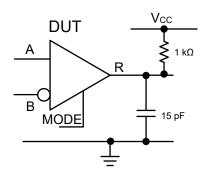


Figure 7-5. Measurement of Receiver Characteristics



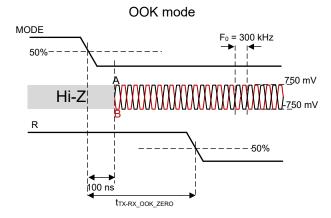
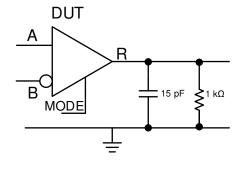


Figure 7-6. Transmit to Receive Mode Change with Low Output



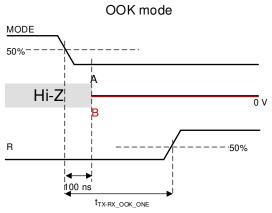


Figure 7-7. Transmit to Receive Mode Change with High Output



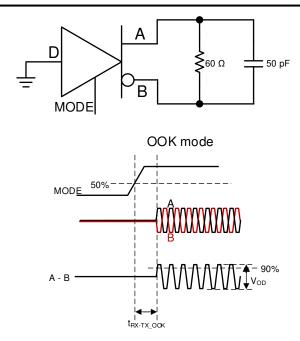


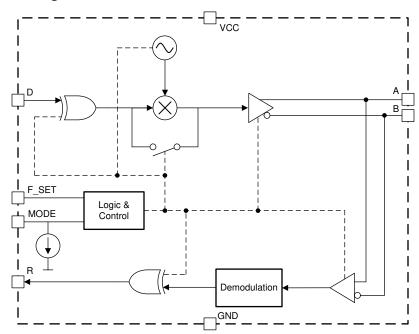
Figure 7-8. Receive to Transmit Mode Change

8 Detailed Description

8.1 Overview

THVD8010 enables power line communication using RS-485 physical layer signaling. An integrated OOK modulator enables RS-485 data to be directly coupled onto existing power cables via series capacitors without any updates to the MCU or the controller. The THVD8010 receiver extracts the data from the power cables through series capacitors by using a precise bandpass filter and a demodulator.

8.2 Functional Block Diagrams



8.3 Feature Description

8.3.1 OOK Modulation with F_SET pin

Data at the D input is modulated with the carrier frequency (f_0) which is set via the F_SET pin. Figure 8-1 illustrates the modulation scheme. A high level at the D input is driven to the mid-level with zero differential voltage (V_{OD}). A low level at the D input is modulated at the carrier frequency. It is recommended to use a carrier frequency that is 10x higher than the data rate. Higher data rates are possible at the expense of increased pulse width distortion with the use of lower ratios.

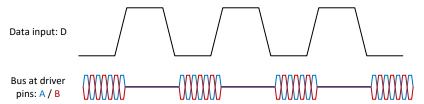


Figure 8-1. OOK Modulation Scheme



 f_0 is programmable by changing the external resistor (R_{F_SET}) value connected to ground. Table 8-1 shows the carrier frequency for the each recommended resistor value.

Table 8-1. OOK f₀ versus R_{F SET}

R _{F_SET} (kΩ)	OOK f ₀ (kHz)
77	125
50	187.5
31.9	300

The oscillator used to generate the carrier frequency features spread spectrum clocking to reduce emissions.

8.3.2 OOK Demodulation

The OOK signal received at the A and B inputs go through a bandpass filter and a peak detector to regenerate the original data stream. Figure 8-2 shows the OOK input and the R output waveforms. The bandpass filter characteristics will adapt to optimal settings automatically based on the carrier frequency, set via R_{F SET}.

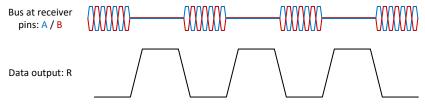


Figure 8-2. OOK Demodulation

8.3.3 Transmitter Timeout

The driver path incorporates a timeout feature to prevent a faulty node from occupying the bus indefinitely in a multi-drop application.

The driver stops transmitting and the outputs go high impedance if the D input doesn't detect an edge (either rising or falling) for longer than $t_{TX_TIMEOUT}$. One of the following events brings the device back to normal operation.

- · Any edge at D input
- · Toggle MODE pin

The transmit path resumes operation within t_{MODE}.

8.3.4 Polarity Free Operation

THVD8010 is immune to A and B polarity at the receiver input in OOK mode. The receiver data comparator only checks for the receive input signal magnitude, ignoring the polarity, to determine its logic level. Note that reversing the polarity does result in degraded pulse width distortion.

8.3.5 Glitch Free Mode Change

The device incorporates a delay of up to t_{MODE} when changing the state of the MODE pin. This feature ensures that there are no glitches at the A, B and R outputs when transitioning between transmit and receive modes.

8.3.6 Integrated IEC ESD and EFT Protection

Internal ESD protection circuits protect the transceiver against electrostatic discharges (ESD) according to IEC 61000-4-2 of up to ± 8 kV contact and against electrical fast transients (EFT) according to IEC 61000-4-4 of up to ± 4 kV. This integrated protection eliminates the need of external components reducing the system BOM.

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8.4 Device Functional Modes

Table 8-2. Functional Modes

F_SET Configuration	Device Functional Mode
R_{F_SET} between F_SET and GND	OOK mode, f_0 set by the R_{F_SET} value
F_SET at high impedance	
F_SET at V _{CC}	Invalid, not recommended for normal operation
F_SET short to GND	

8.4.1 OOK Mode

Data at the D input is modulated with the carrier frequency set by the R $_{F_SET}$ value when the device is transmitting (MODE = V_{CC}). See Section 8.3.1 section for more details. In receiving (MODE = GND), the device expects an OOK modulated signal at the A and B inputs. The data is demodulated and sent out via R pin. See Section 8.3.2 section for more details.

Table 8-3. Driver function table for OOK mode

	INPUTS		OUT	FUNCTION	
F_SET	MODE	D	Α	В	
R _{F_SET} (See Table 8-1)	Н	H or Z	Bias to V _{CM}	Bias to V _{CM}	Driver is actively biased to V _{CM} on the bus
	Н	L	Oscillating	Oscillating	Bus actively driven at carrier frequency
	L or Z	X	Z	Z	Driver disabled, device in receive mode

Table 8-4. Receiver function table for OOK mode

	INPUTS		OUTPUT	FUNCTION	
F_SET	MODE	Input	R		
R _{F_SET} (See Table 8-1)	L or Z	Oscillating at F_SET and V _{ID} > V MAG_ZERO	L	Receive valid bus low	
	L or Z	Oscillating at F_SET and V MAG_ONE < VID < VMAG_ZERO	?	Receive invalid bus, output indeterminate	
	L or Z	Oscillating at F_SET and V _{ID} < V MAG_ONE	н	Receive valid bus high	
	L or Z	Z / not oscillating	Н	Receive valid bus high	
	L or Z	OPEN, SHORT, IDLE (V _{ID} = 0 V)	Н	Failsafe high output	
	Н	Х	Z	Receiver disabled, device in transmit mode	

8.4.2 Thermal shutdown (TSD)

The THVD8010 has a protection feature called thermal shutdown. When the junction temperature reaches T_{SD} , the device enters thermal shutdown protection mode. This mode disables the driver and receiver outputs, which will halt all communication through the device. Normal operation resume once the junction temperature drops out of thermal shutdown, which is typically T_{SD} - T_{HYS} .



9 Application and implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application information

The THVD8010 is able to transmit data over an AC coupled power line pair using On-Off Keying (OOK).

9.2 Typical application (OOK mode)

In order to combine data and power over a single pair of wires, capacitors and inductors are used in a bias-tee configuration. High-frequency differential data is AC-coupled onto the bus lines via series capacitances while power is DC-coupled via series inductances. The values of these components will depend on the carrier frequency, number of nodes on the bus, and the power delivery requirements (i.e., voltage and total current sourced or consumed by a given node).

In Figure 9-1, there is an optional rectifier network pictured on the bus lines. This network of diodes can ensure that the node is receives power correctly from the bus wires, even if the lines get swapped.

A termination resistance, R_T, is not required for device functionality but can be useful in improving signal integrity in some applications by reducing reflections that can occur at cable ends.

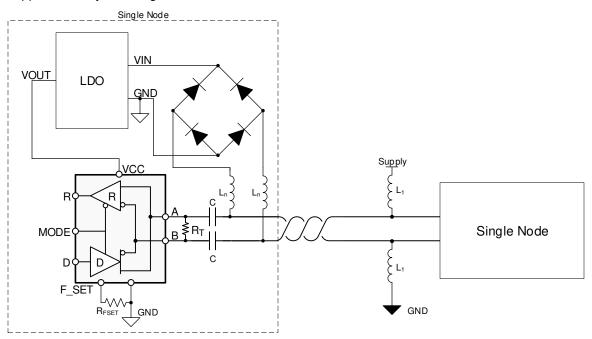


Figure 9-1. Typical power line network with 2 nodes

9.2.1 Design requirements

The main requirements are the values of the bus capacitors and the power inductors. Both of these values are dependant upon the carrier frequency selected.

9.2.1.1 Carrier frequency

This device uses on-off-keying to transmit binary data on the bus. Please read Section 8.3.1 for detailed information. The modulation and demodulation of the data can result in pulse width distortion due to asymmetries in low-to-high and high-to-low transition times. These asymmetries are due to factors like

synchronization of the data to the internal carrier oscillator in the transmit path and the response time of the band-pass filter in the receive path. The impact of these factors can be minimized by choosing a carrier frequency much higher than the data rate required. A frequency ratio of at least 10:1 is recommended.

9.2.2 Detailed design procedure

9.2.2.1 Inductor value selection

It is important to note that the inductor selected must also take power consumption into consideration. The inductor should be sized to handle the maximum anticipated current in addition to the inductance value.

The parallel aggregate impedance should be selected so that the total equivalent impedance at the carrier frequency is $Z \ge 375~\Omega$. This assumes RS-485 loading with 60 Ω termination. If no termination is used in the application, then the total equivalent impedance at the carrier frequency could be reduced to $Z \ge 60~\Omega$. These examples assume that termination is used. Equation 1 shows the parallel aggregate impedance equation for inductors L_1 to L_n . Since the inductance value for each node should be the same, it's simple to determine that each node's impedance should be n times the total equivalent impedance. For example, if there are 4 nodes connected to the bus and the equivalent impedance is 375 Ω , then each node impedance should be 1,500 Ω .

$$Z = Z_1 ||Z_2|| ... ||Z_n$$
 (1)

To determine the suggested inductance value, Equation 2 can be rearranged to determine L_n , as shown in Equation 3.

$$Z_n = 2\pi f_0 L_n \tag{2}$$

$$L_n = \frac{Z_n}{2\pi f_0} \tag{3}$$

 f_0 is the carrier frequency (OOK frequency) used. If the previous 1.5 k Ω impedance per node is assumed with a carrier frequency of 300 kHz, the resulting inductance limit is ~800 μ H per node. Be aware that this is the minimum suggested value per node. Refer to Figure 9-2 as a quick reference on the minimum inductance value to achieve 375 Ω of total aggregate impedance. This value can be multiplied by the number of nodes on the bus to get the minimum inductance per node. Referring to the previous example, if there are 4 nodes and a carrier frequency of 300 kHz, then the minimum aggregate inductance is about 200 μ H, which is 800 μ H when multiplied by 4.

9.2.2.2 Capacitor value selection

Capacitor selection is easier than inductor selection, primarily because capacitance impedance is important to allow higher frequency signals through. However, the capacitor ratings for voltage must be carefully selected to meet the application requirements. Special considerations for hot plug nodes should be made to ensure that voltage transients during hot plugging do not exceed the absolute maximum values. See Section 6.1.

The number of nodes on the bus does not play into the capacitance calculation. The impedance of a capacitor is shown in Equation 4.

$$Z = \frac{1}{2\pi f_0 C} \tag{4}$$

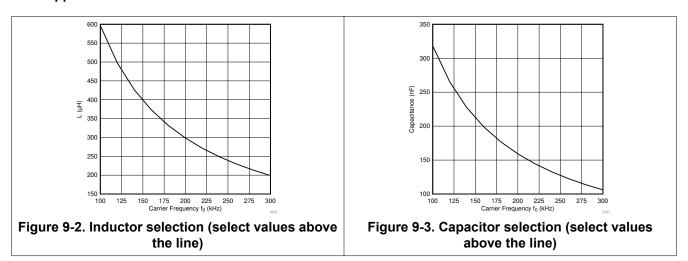
Maintaining $Z \le 5 \Omega$ keeps the impedance low enough at the carrier frequency to allow data to pass through. If the equation is rearranged to calculate C, the result is shown in Equation 5.

$$C = \frac{1}{2\pi f_0 Z} \tag{5}$$

If the previous example of a 300 kHz carrier frequency is used, then a minimum capacitance value of about 106 nF. For a quick reference, refer to Figure 9-3.



9.2.3 Application Curves



10 Power supply recommendations

To ensure reliable operation at all data rates and supply voltages, the supply should be decoupled with a 100 nF ceramic capacitor and a 1 μ F capacitor (for ESD sensitive designs) located as close to the supply pins as possible. This helps to reduce supply voltage ripple present on the outputs of switched-mode power supplies and also helps to compensate for the resistance and inductance of the PCB power planes.



11 Layout

11.1 Layout guidelines

Robust and reliable bus node design often requires the use of external transient protection devices in order to protect against surge transients that may occur in industrial environments. Since these transients have a wide frequency bandwidth (from approximately 3 MHz to 300 MHz), high-frequency layout techniques should be applied during PCB design.

- 1. Place the protection circuitry close to the bus connector to prevent noise transients from propagating across the board.
- 2. Use V_{CC} and ground planes to provide low inductance. Note that high-frequency currents tend to follow the path of least impedance and not the path of least resistance.
- 3. Place F_SET components near the pin to keep capacitance load below recommended value
- 4. Use a pull up or down resistor on mode to set a default state
- 5. Apply 100-nF to 220-nF and a 1-uF decoupling capacitors as close as possible to the V_{CC} pins of transceiver, UART and/or controller ICs on the board.
- 6. Use at least two vias for V_{CC} and ground connections of decoupling capacitors and protection devices to minimize effective via inductance.
- 7. Use 1-k Ω to 10-k Ω pull-up and pull-down resistors for enable lines to limit noise currents in theses lines during transient events.
- 8. Insert pulse-proof resistors into the A and B bus lines if the TVS clamping voltage is higher than the specified maximum voltage of the transceiver bus pins. These resistors limit the residual clamping current into the transceiver and prevent it from latching up.
- 9. While pure TVS protection is sufficient for surge transients up to 1 kV, higher transients require metal-oxide varistors (MOVs) which reduce the transients to a few hundred volts of clamping voltage, and transient blocking units (TBUs) that limit transient current to less than 1 mA.

11.2 Layout Example

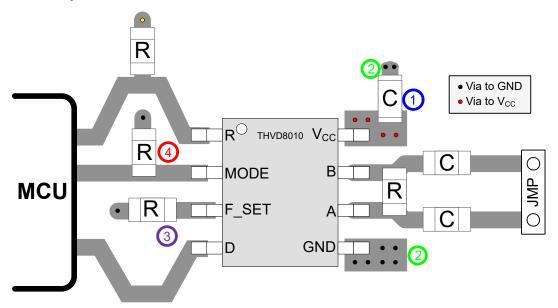


Figure 11-1. Layout Example (OOK)



12 Device and Documentation Support

12.1 Device Support

12.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

12.4 Trademarks

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12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

TI Glossary

This glossary lists and explains terms, acronyms, and definitions.

Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

Product Folder Links: THVD8010



PACKAGE OPTION ADDENDUM

11-Nov-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
THVD8010DDFR	ACTIVE	SOT-23-THIN	DDF	8	3000	Green (RoHS & no Sb/Br)	SN	Level-1-260C-UNLIM	-40 to 125	8010	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

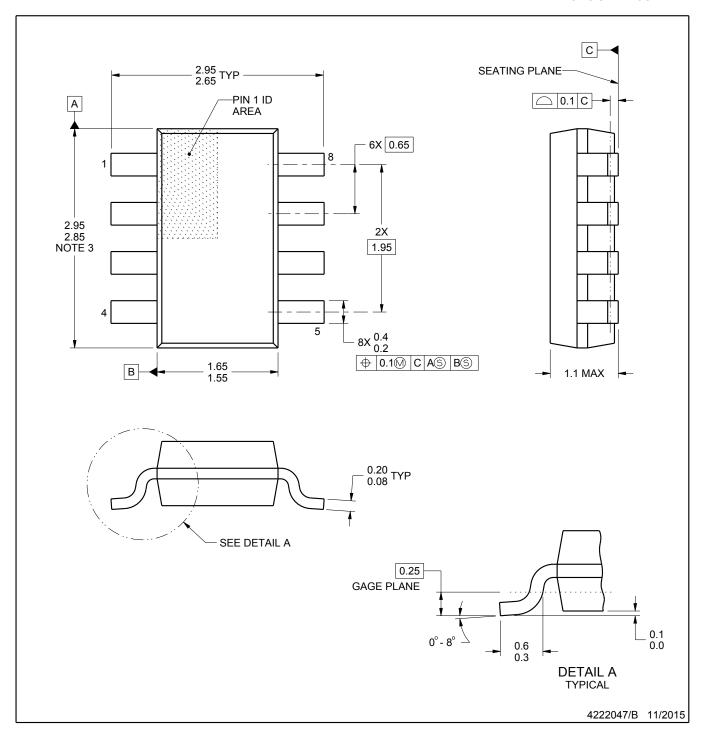
- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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PLASTIC SMALL OUTLINE



NOTES:

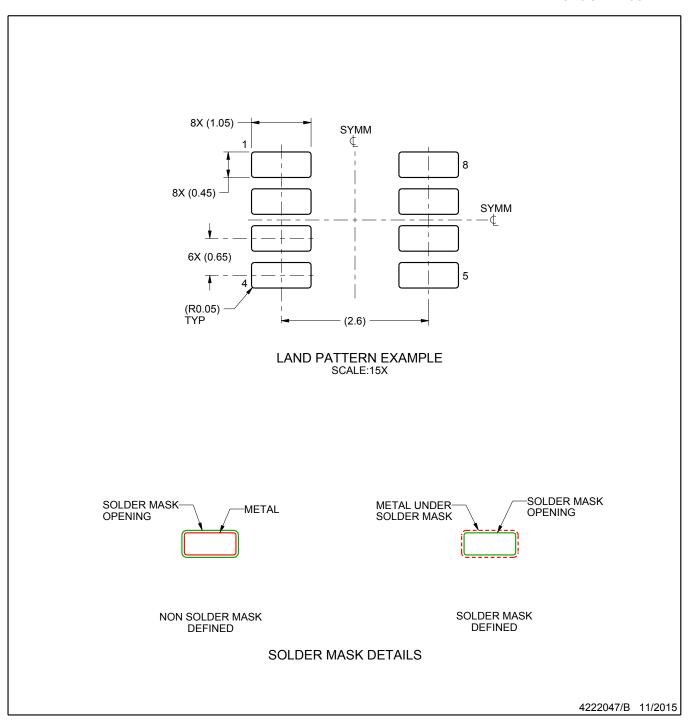
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.



PLASTIC SMALL OUTLINE

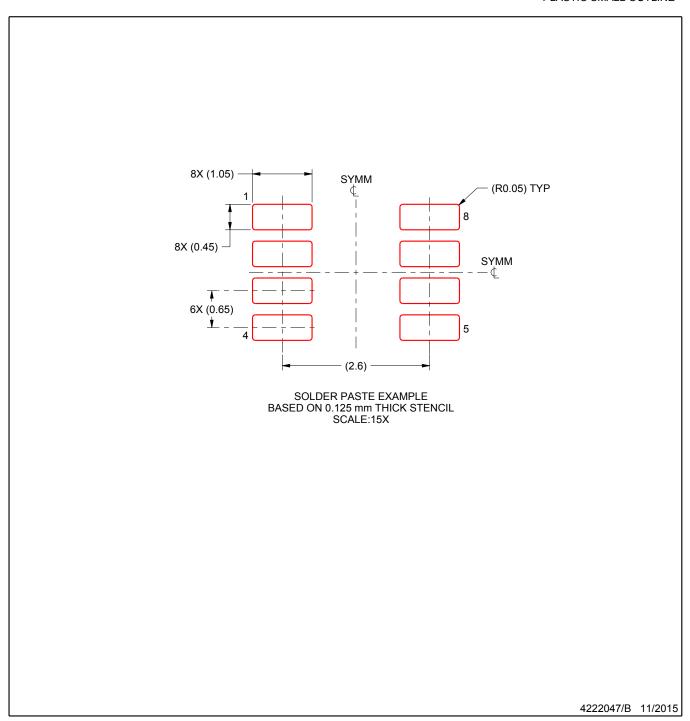


NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



PLASTIC SMALL OUTLINE



NOTES: (continued)

- 6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 7. Board assembly site may have different recommendations for stencil design.



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